

"Alexandru Ioan Cuza" University of Iasi

# Transparent thin film of zinc oxide for solar cells applications fabricated by pulsed laser deposition

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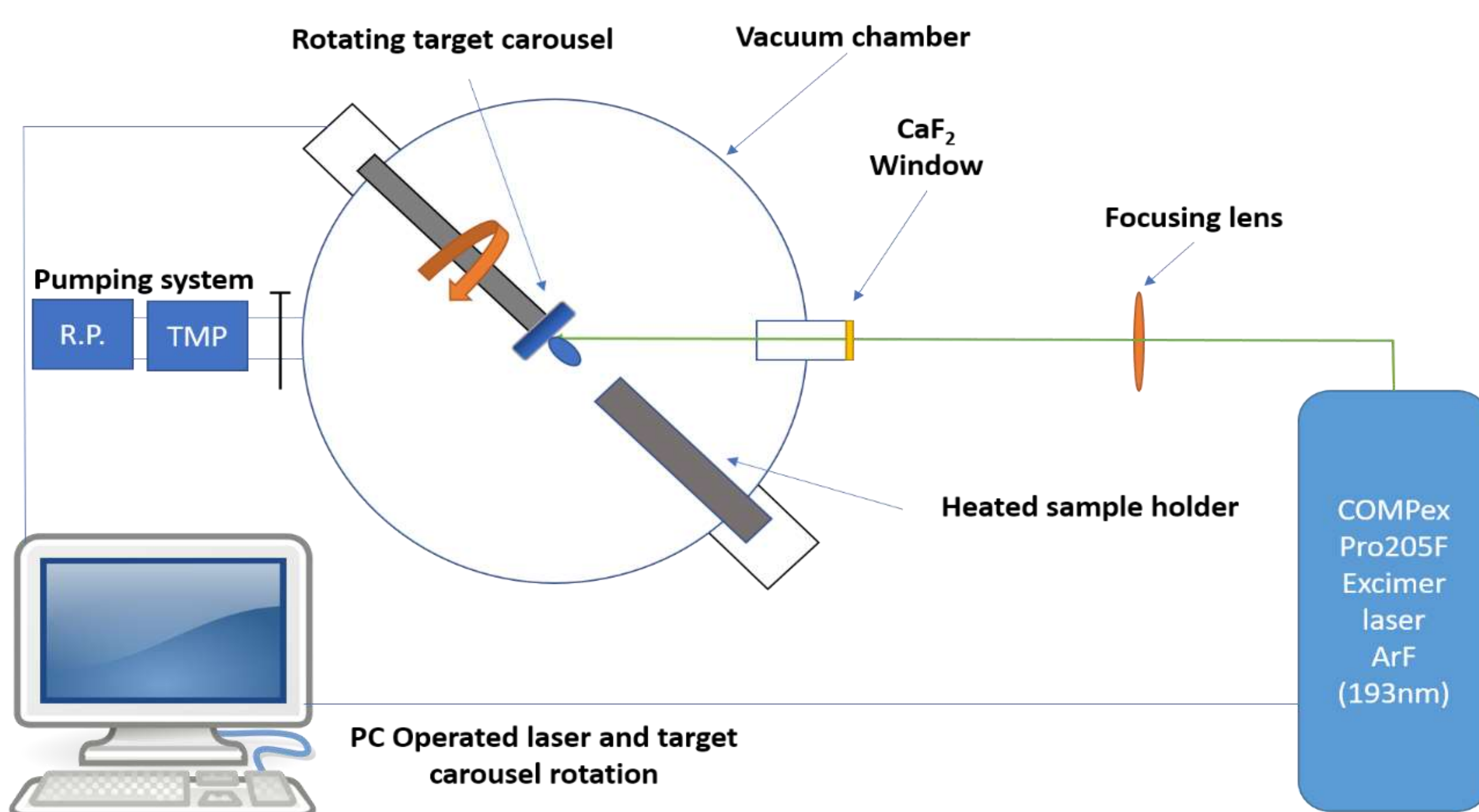
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## Motivation

- ❖ facile zinc oxide (ZnO) synthesis of zinc oxide based nanomaterials with specific properties is a great challenge due to its excellent industrial applications in the field of semiconductor and solar cells.
- ❖ zinc oxide (ZnO) thin films and nanostructures attracted a great interest in last decades owing to their unique properties such as large exciton binding energy (60 meV), direct wide-band gap of about 3.4 eV at room temperature, high optical transparency in the visible region, low electrical resistivity as well as high electrochemical stability, high electron mobility, non-toxicity and abundance in nature

## Experimental Device

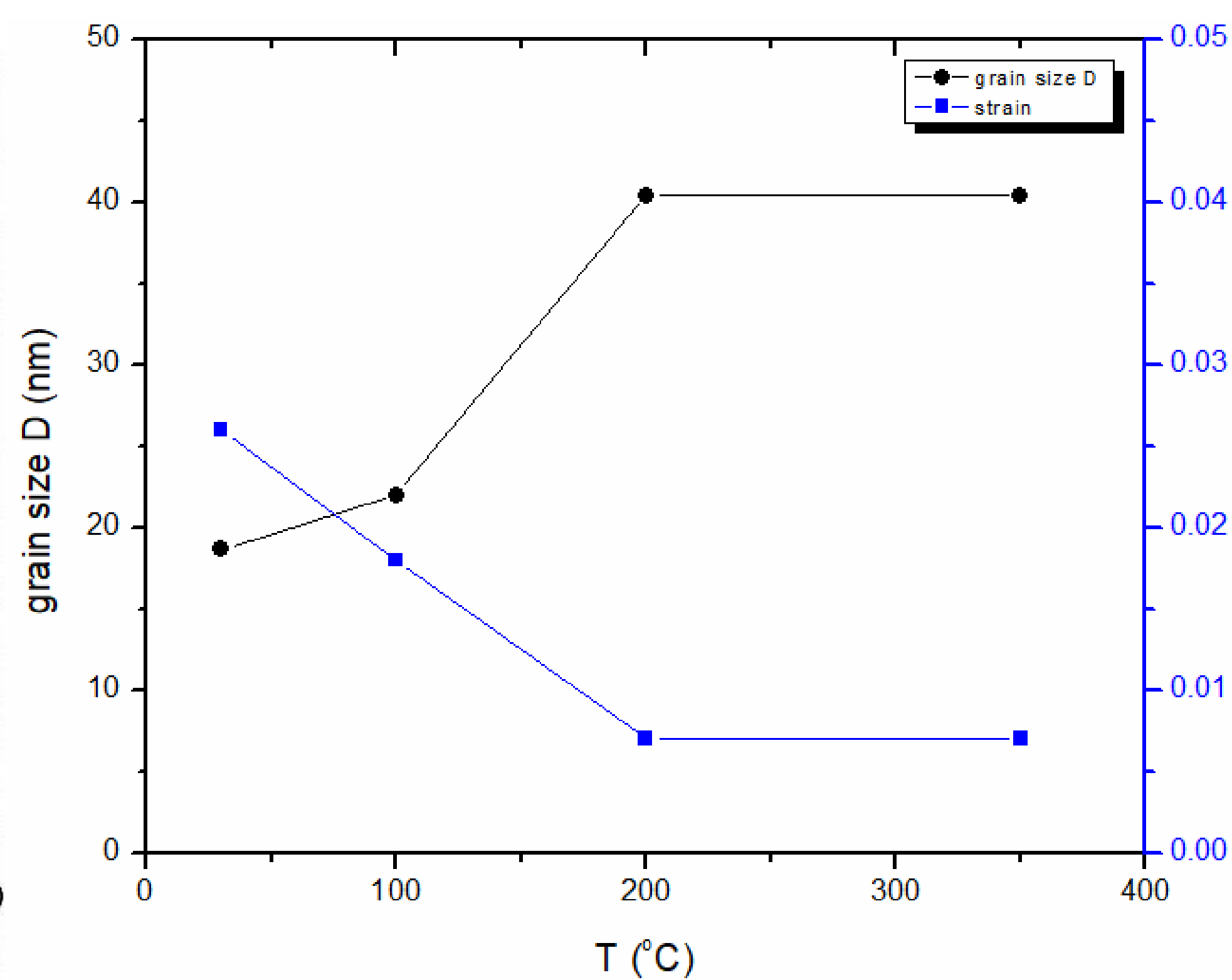
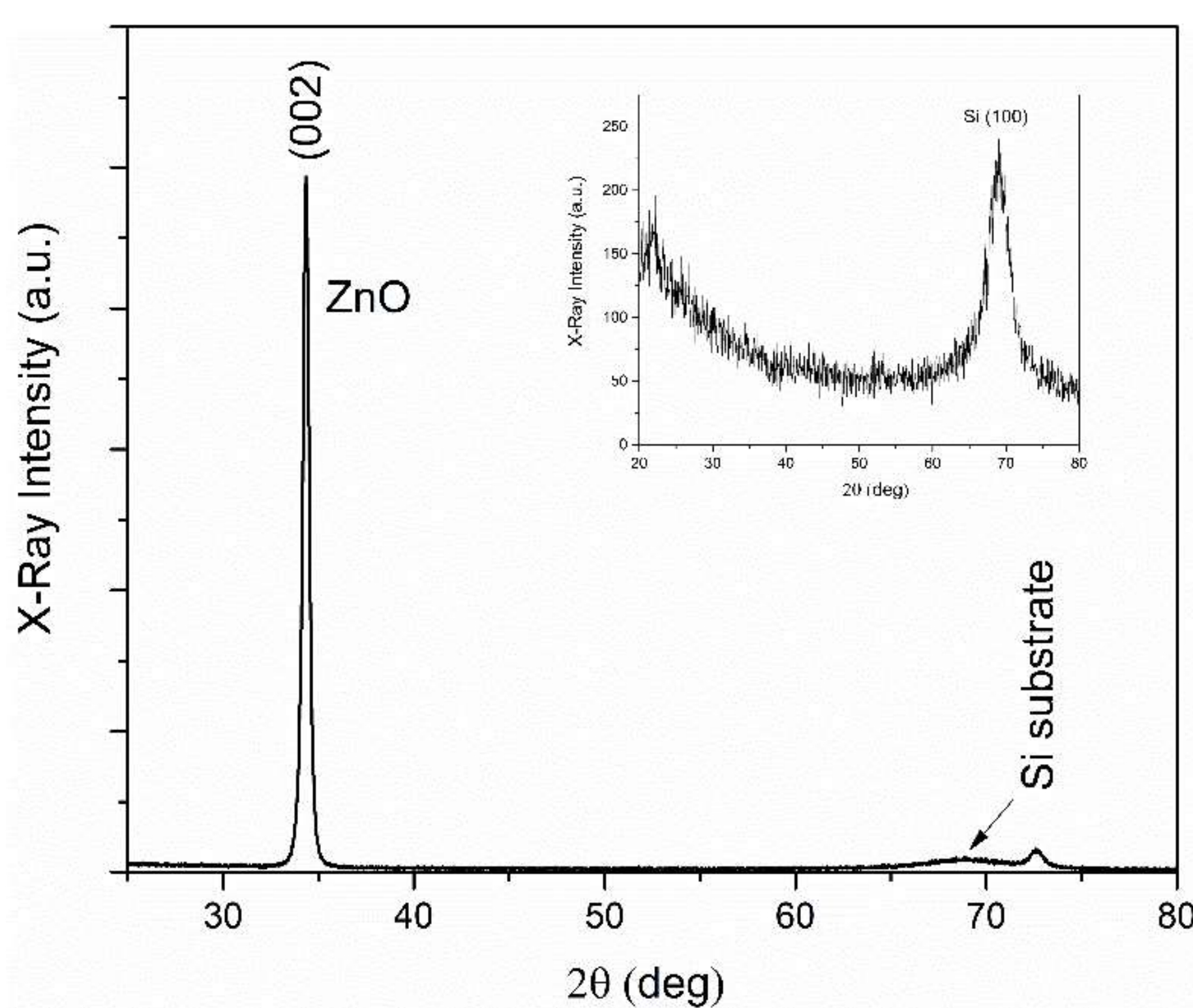


## Pulsed laser deposition

- ❖ Pulsed laser deposition (PLD) has been studied and employed as relatively simple and reliable technique for depositing a wide range of materials for novel applications
- ❖ Stoichiometric process
- ❖ Excimer laser represent one of the most popular gas-based lasers, generating intense short pulses in the ultraviolet spectrum
- ❖ Excimer lasers have the ability to produce a wide range of processing power with variable repetition rates
- ❖ Clean method with no chemical contaminants

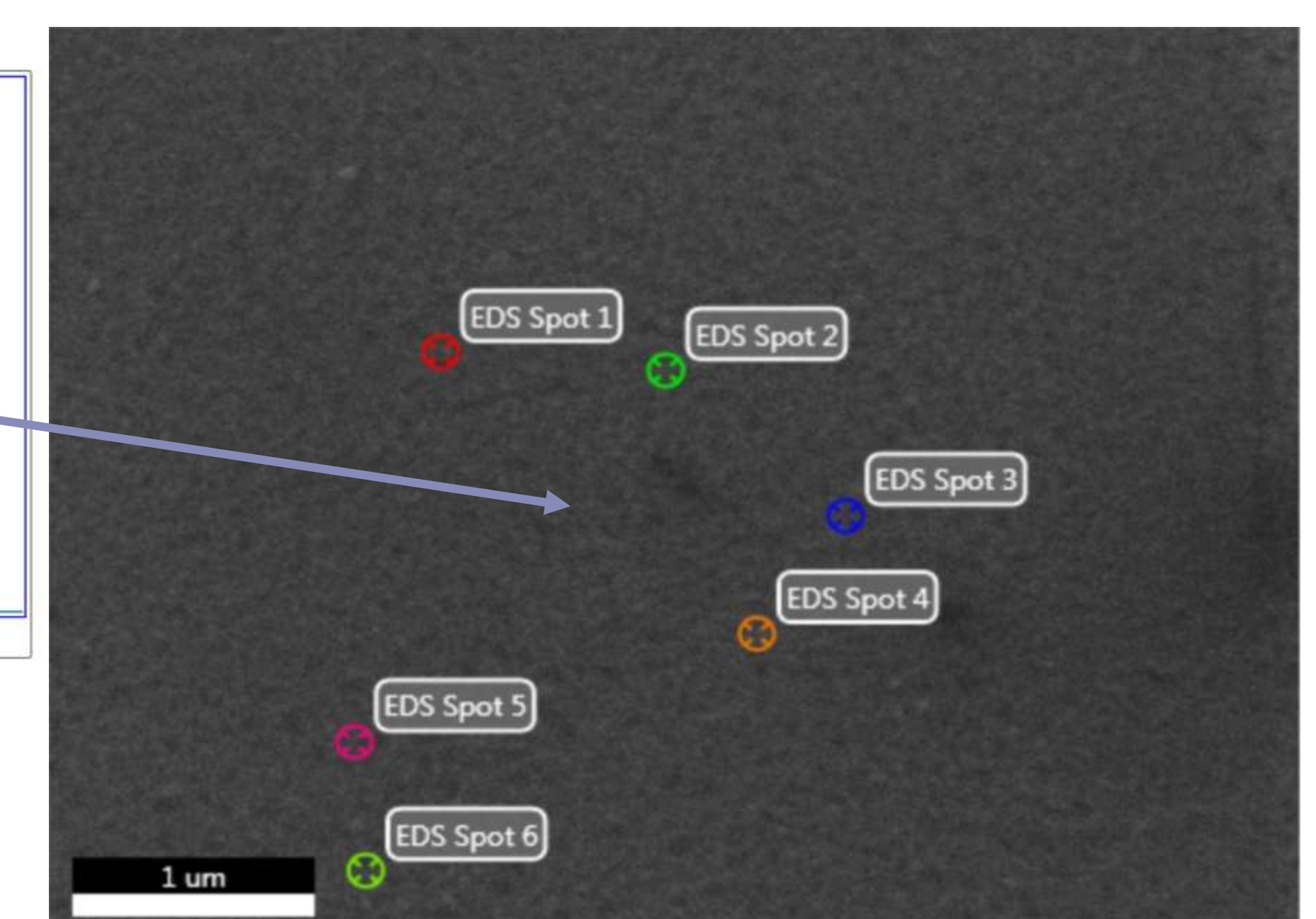
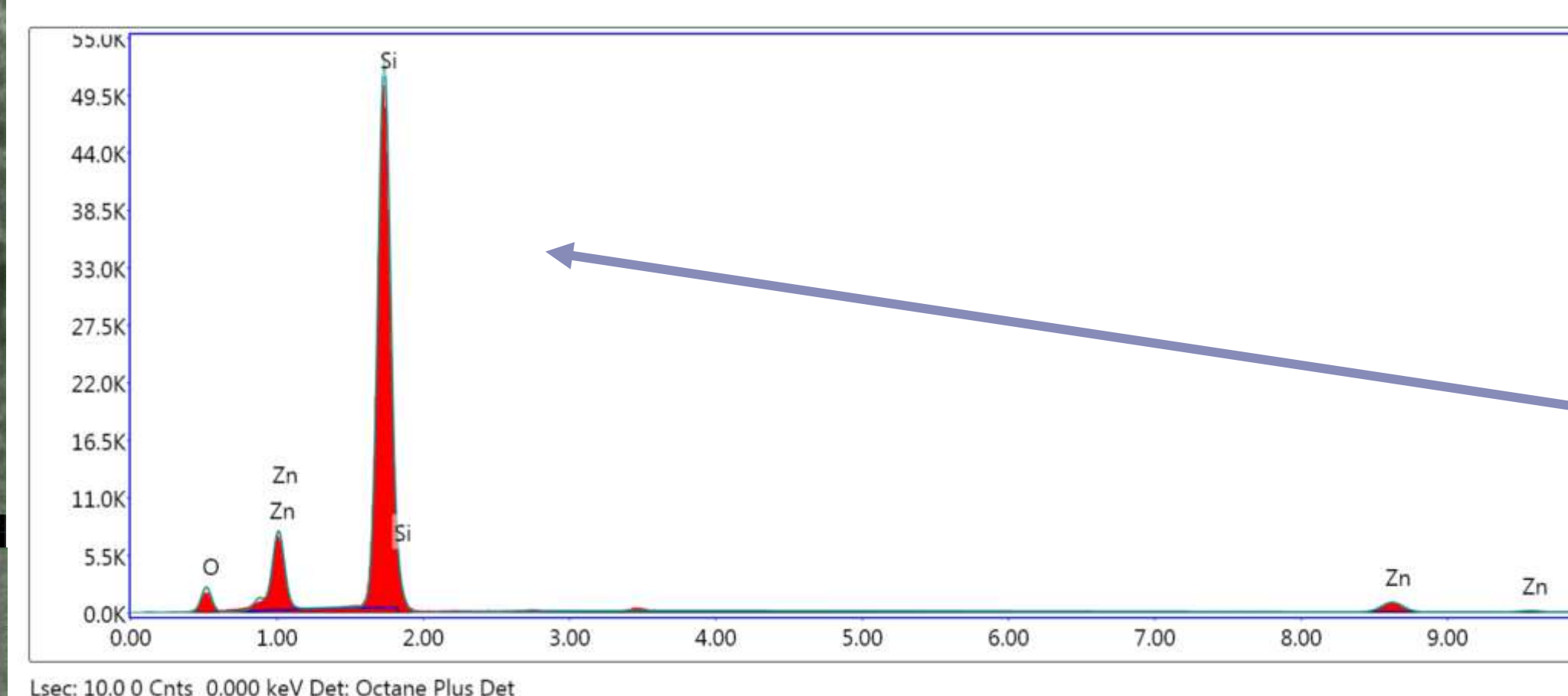
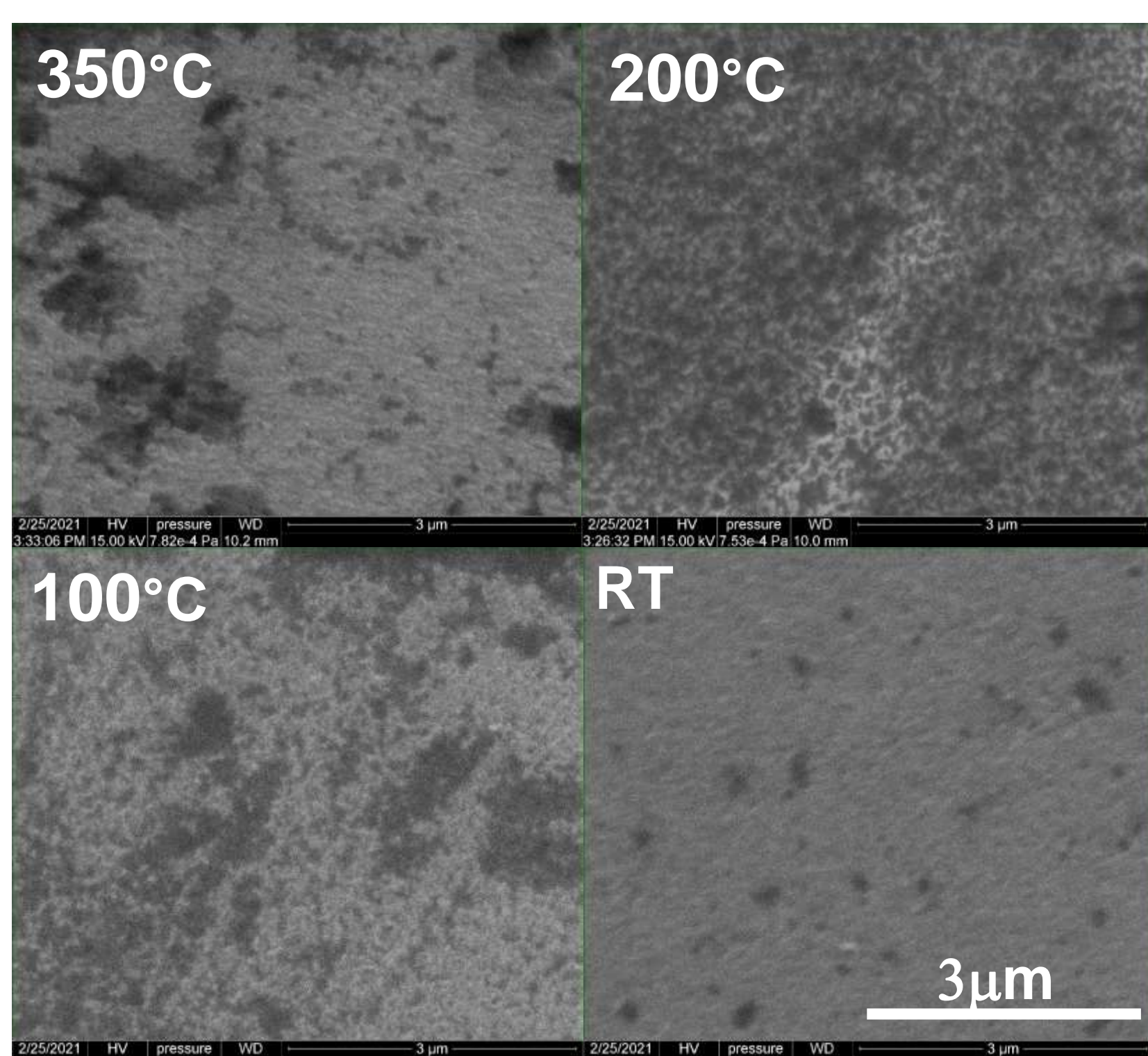
## Results

### Structural properties – XRD measurements



- ❖ Highly oriented ZnO thin films – (002) plane – are deposited by PLD
- ❖ Calculated crystalline distance  $d$  are temperature depend – crystalline distance increases with respect to substrate temperature
- ❖ Increasing substrate temperature to about 350°C the thin films become almost stress free.

### Surface morphology and chemical composition – SEM and EDS measurements



- ❖ Surface morphology of the ZnO thin films is in good agreement with the calculated values from XRD measurements.
- ❖ EDS measurements indicated highly pure and uniform films
- ❖ the ratio of Zn to Si (the substrate) was about  $13.2 \pm 0.2\%$

## Conclusions

- ✓ Highly oriented ZnO thin films can be obtained by PLD
- ✓ Substrate temperature is crucial for crystalline size and surface morphology of ZnO

## Future prospects

- ✓ . Creating a heterojunction of n-ZnO/p-Si has the potential of integrating it in a wide range of application such as gas sensors, solar cells, photodiodes and many others.